

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Yuichi OKUDA et al.

Appln. No.:

Filed: Herewith

For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

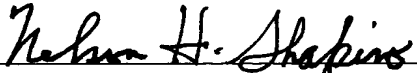
Sir:

Applicants wish to make of record the documents cited in predecessor U.S. Application No. 10/185,055 filed July 1, 2002, which is a division of U.S. Application No. 10/036,374 filed January 7, 2002, which is a continuation of U.S. Application No. 09/629,173 filed July 31, 2000, whether cited by Applicants or by the Patent Office. The documents are listed on the attached Form-1449.

Respectfully submitted,

NHS:sjk

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By: 
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Reg. No. 17,095

July 8, 2003

FORM PTO-1449				Atty. Docket No. XA-9339C		Appln. No.	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>							
				Applicant Yuichi OKUDA et al.			
				Filing Date HEREWITH		Group	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA	6,194,932	2/27/01	Takemae et al.	327	158	
	AB	6,457,688	12/00	Tamura et al.	375	348	
	AC	6,069,508	5/30/00	Takai	327	61	
	AD	6,172,537	1/01	Kanou et al.	327	99	
	AE	5,754,838	5/19/98	Shibata et al.	395	559	
	AF	5,953,284	9/14/99	Baker et al.	365	233	
	AG	6,166,990	12/26/00	Ooishi et al.	365	233	
	AH	6,222,406	4/01	Noda et al.	327	269	
	AI	6,081,142	6/27/00	Douchi et al.	327	158	
	AJ	5,936,441	8/10/99	Kurita	327	141	
	AK	5,926,053	7/20/99	McDermott et al.	327	298	
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Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
	AL	2000-188540	7/00	Japan			cited by Examiner
	AM	2000-124796	4/00	Japan			cited by Examiner
	AN	2000-183730	6/00	Japan			cited by Examiner
	AO	2-90666	3/30/90	Japan			Abstract
	AP	11-55145	2/26/99	Japan			Abstract
	AQ	10-171774	6/26/98	Japan			Abstract
OTHER (including author, title, date, pertinent pages, etc.)							
	AR	Johnson et al., "A Variable Delay Line PLL for CPU-Coprocessor Synchronization", <i>IEEE Journal of Solid-State Circuits</i> , Vol. 23, No. 5, pp. 1218-1223, October 1998					
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							

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				Filing Date HEREWITH		Group	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA*	6,191,632	12/20/01	Iwata	327	295	
	AB*	5,883,534	3/16/99	Kondoh et al.	327	156	
	AC*	6,377,511	4/23/02	Okuda et al.	365	233	
	AD*	6,373,303	4/16/02	Akita	327	156	
	AE*	5,619,148	4/8/97	Guo	327	3	
	AF*	2001/0021953	09/13/01	Nakashima	710	5	
	AG*	2002/0008589	01/24/02	Lanoman et al.	331	34	
	AH*	2002/0033737	3/21/02	Staszewski et al.	331	17	
	AI*	6,452,859	09/17/02	Shimano et al.	365	230.06	
	AJ*	6,172,537	01/09/01	Kanou et al.	327	99	
	AK*	6,518,813	02/11/03	Usui	327	291	
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OTHER (including author, title, date, pertinent pages, etc.)							
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				Filing Date HEREWITH		Group	
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Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
	AA+	6,463,008	10/08/02	Okuda et al.	365	233	
	AB+	2001/0017558	08/30/01	Hanzawa et al.	327	165	
	AC+	6,336,901	01/08/02	Itonaga et al.	600	499	
	AD+	6,281,725	08/28/01	Hanzawa et al.	327	152	
	AE+	6,269,051	07/31/01	Funaba et al.	365	233	
	AF+	6,222,792	04/24/01	Hanzawa et al.	365	233	
	AG+						
	AH+						
	AI+						
	AJ+						
	AK+						
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	AM						
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	AO						
	AP						
	AQ						
OTHER (including author, title, date, pertinent pages, etc.)							
	AR						
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